

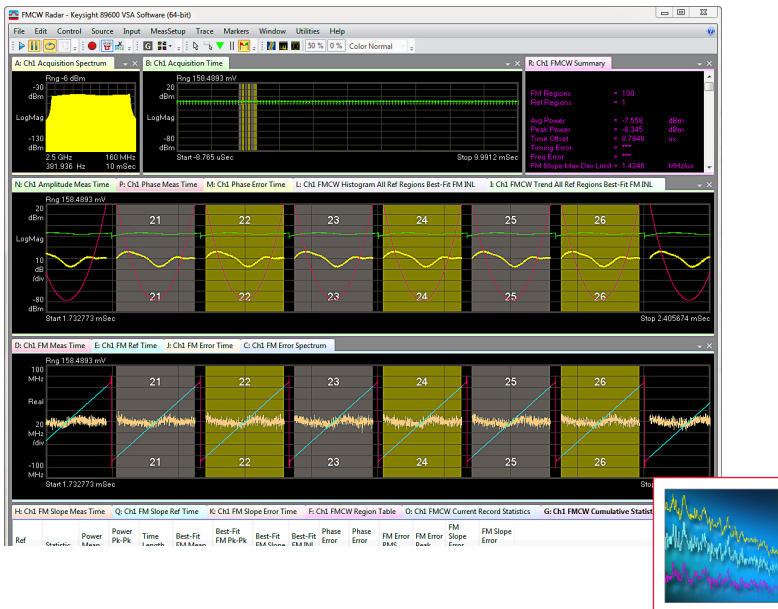
Keysight

LTE and LTE-Advanced FDD/TDD X-Series Measurement Application

N9080B and W9080B

N9082B and W9082B

Technical Overview



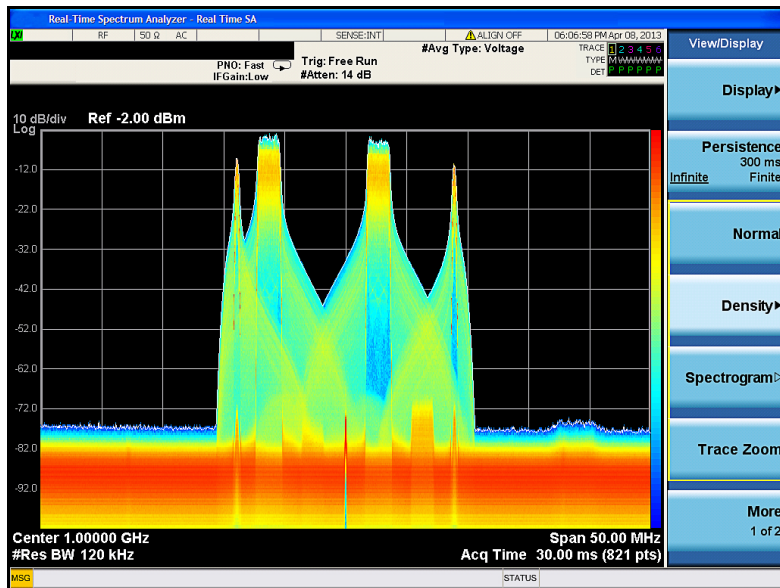
- Perform LTE plus LTE-Advanced FDD and TDD base station (eNB) and user equipment (UE) transmitter tests
- Accelerate measurements with one-button RF conformance tests as defined by 3GPP TS 36.141 and 36.521 specification
- Analyze carrier-aggregated signal of up to 5 contiguous/noncontiguous component carriers
- Use hardkey/softkey manual user interface and SCPI remote user interface
- Leverage built-in, context-sensitive help
- Extend test assets with transportable licenses between X-Series signal analyzers

LTE/LTE-Advanced FDD and TDD Measurement Applications

The LTE/LTE-Advanced FDD and TDD measurement applications transform the X-Series signal analyzers into 3GPP LTE/LTE-Advanced standard-based RF transmitter testers. The applications provide fast, one-button RF conformance measurements to help you design, evaluate, and manufacture your LTE and LTE-Advanced base stations (eNB) and user equipment (UE). The measurement applications closely follow the 3GPP standard, allowing you to stay on the leading edge of your design and manufacturing challenges.

X-Series measurement applications

X-Series measurement applications increase the capability and functionality of Keysight signal analyzers to speed time to insight. They provide essential measurements for specific tasks in general-purpose, cellular communications, wireless connectivity and digital video applications, covering more than 40 standards or modulation types. Applications are supported on both benchtop and modular, with the only difference being the level of performance achieved by the hardware you select.



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Top Features

With the LTE/LTE-Advanced FDD and TDD measurement application, you can perform RF transmitter measurements on eNB and UE devices in time, frequency, and modulation domains. Measurement setups are simplified with automatic detection of downlink channels and signals. For eNB conformance testing, measurement is simplified by recalling E-TM presets according to 3GPP TS 36.141 specifications.

Downlink eNB measurements

LTE downlink modulation analysis

Figure 1 is an LTE downlink modulation analysis measurement showing constellation, detected allocation, frame summary, and error summary information. Measurements are color-coded based on channel type for ease of troubleshooting.

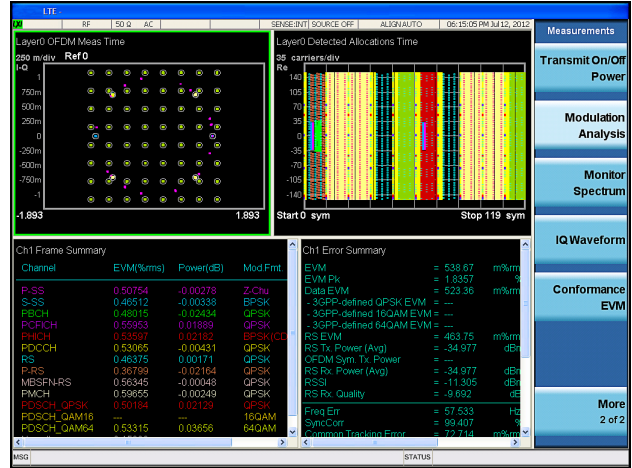


Figure 1

LTE-Advanced downlink analysis

An LTE-Advanced downlink modulation analysis showing constellation of five component carriers side-by-side is displayed in Figure 2.

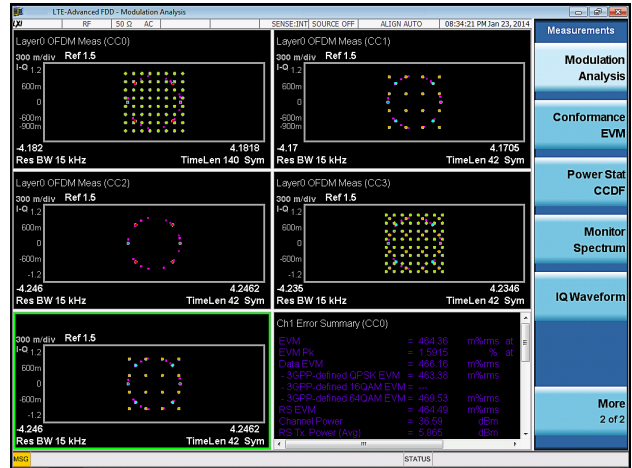


Figure 2

Downlink transport layer channel decoding

Figure 3 shows a downlink transport layer channel decoding measurement with decoded information for PBCH, PDCCH, PCFICH, and PHICH channels. Similar capability is also available for uplink.

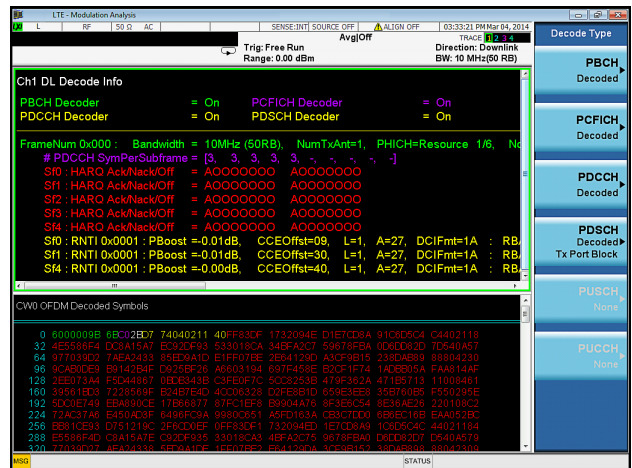


Figure 3

Top Features (continued)

Downlink eNB measurements (continued)

LTE-Advanced cross-carrier summary

LTE-Advanced cross-carrier summary trace showing time alignment error (TAE) and channel power of each CC relative to CC0 is displayed in Figure 4.

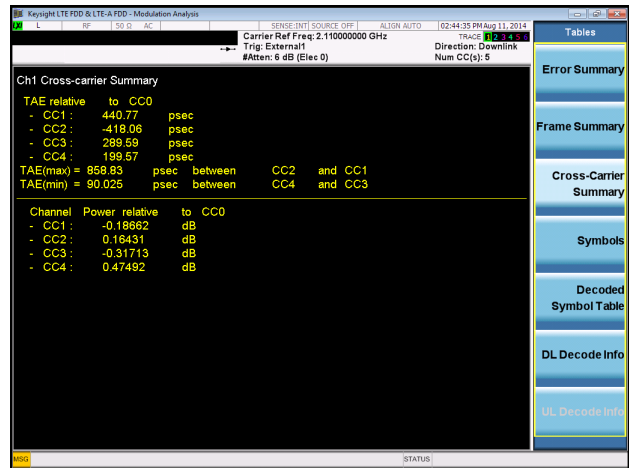


Figure 4

LTE-Advanced ACLR measurement

Figure 5 shows an LTE-Advanced ACLR measurement with five contiguous component carriers.

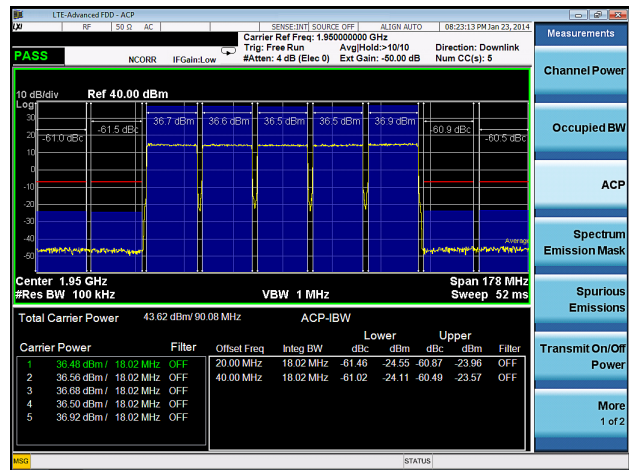


Figure 5

LTE-Advanced cumulative ACLR

LTE-Advanced cumulative ACLR (CACLR) for non-contiguous carrier aggregation is shown in Figure 6.

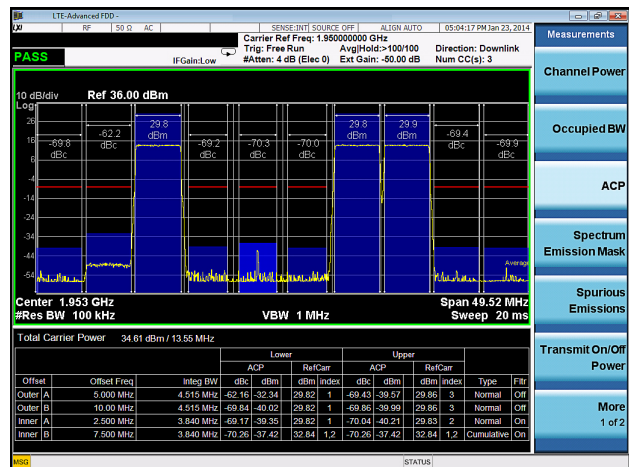


Figure 6

Top Features (continued)

Downlink eNB measurements (continued)

Transmit ON/OFF power measurement

Figure 7 shows a transmit ON/OFF power measurement of an LTE-Advanced TDD downlink signal with two component carriers.

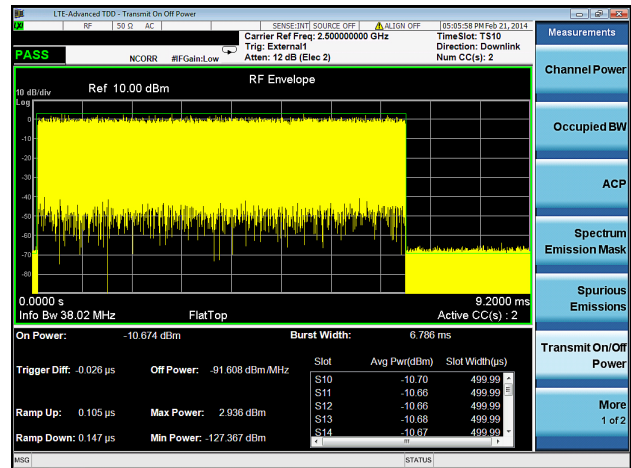


Figure 7

SEM measurement

Figure 8 shows how an SEM measurement can be made on a single carrier LTE or up to five component carrier LTE-Advanced signals simultaneously.

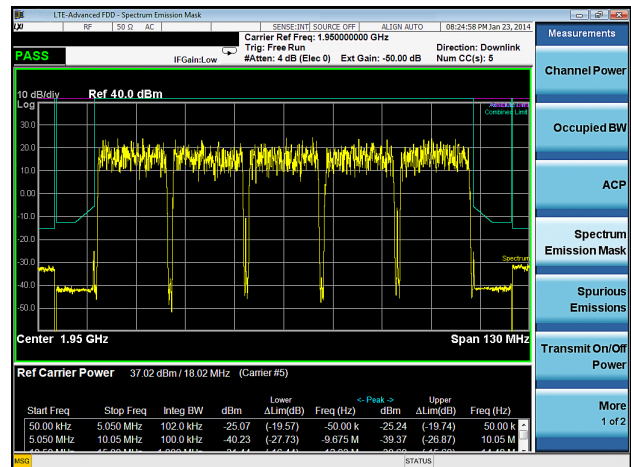


Figure 8

LTE-Advanced non-contiguous carrier aggregation SEM measurement

An LTE-Advanced non-contiguous carrier aggregation SEM measurement with a special cumulative mask inside the sub-block gap is shown in Figure 9.

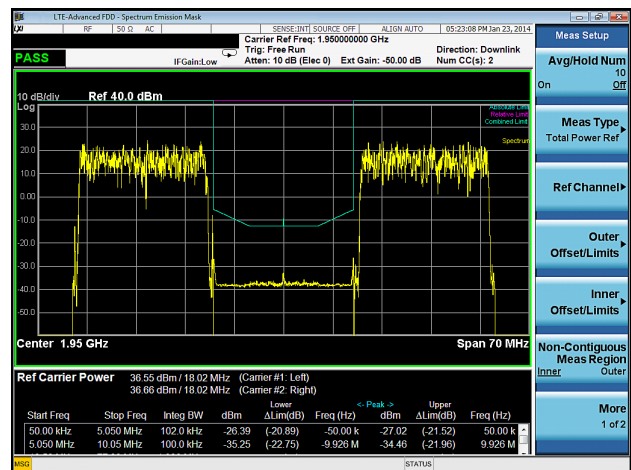


Figure 9

Top Features (continued)

Uplink UE measurements

Uplink modulation analysis

Uplink modulation analysis measurement showing constellation, EVM vs. subcarrier, detected allocation, and EVM vs. symbol information for two component carriers. Measurements are color-coded based on channel type and up to 12 markers with marker coupling between measurements are available for easier troubleshooting. (Figure 10)



Figure 10

Conformance EVM measurement

Conformance EVM measurement showing all required modulation quality metrics. This measurement is optimized for manufacturing because of its fast measurement speed. (Figure 11)

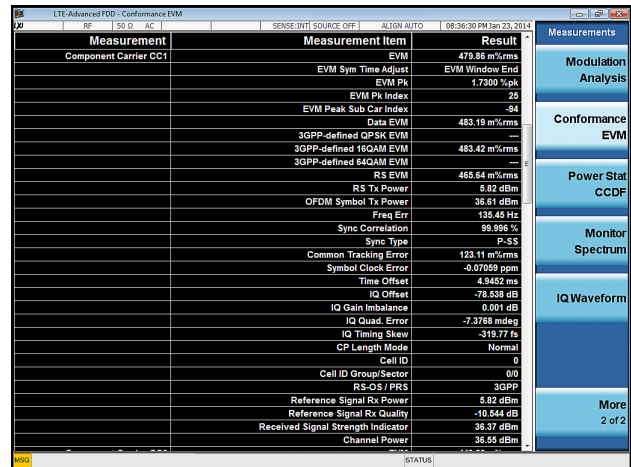


Figure 11

Real-time view of LTE-Advanced FDD uplink

Figure 12 shows a real-time view of LTE-Advanced FDD uplink with simultaneous PUCCH and frequency hopped PUSCH signal configuration using the RTSA option on a PXA or MXA signal analyzer.

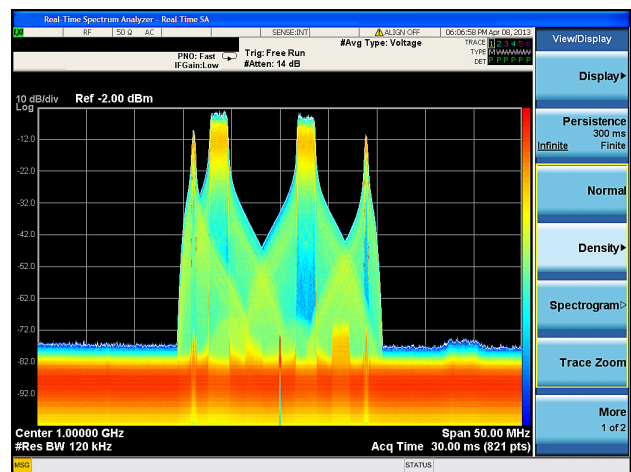


Figure 12

Measurement Summary

One-button standards-based measurements

Required base station (eNB) RF transmitter measurements

3GPP TS36.141 paragraph #	Transmitter test	E-TM required	N9080B & W9080B (FDD) N9082B & W9082B (TDD) measurement applications ¹
6.2	Base station output power	E-TM 1.1	Channel power ²
6.3.2	Total power dynamic range	E-TM 2 E-TM 3.1	OFDM symbol Tx. power (OSTP) ³
6.4	Transmit ON/OFF power (TDD only)	E-TM1.1	Transmit ON/OFF power (N9082B only) ⁴
6.5.1	Frequency error	E-TM 2 E-TM 3.1	Frequency error ³
6.5.2	Error vector magnitude	E-TM 3.2 E-TM 3.3	EVM ³
6.5.3	Time alignment error (TAE)	E-TM 1.1	MIMO summary or cross-carrier summary ⁵
6.5.4	DL RS power	E-TM 1.1	RS Tx power (RSTP) ³
6.6.1	Occupied bandwidth	E-TM 1.1	Occupied BW
6.6.2	Adjacent channel leakage power ratio (ACLR)	E-TM 1.1 E-TM 1.2	ACP
6.6.2.6	Cumulative ACLR (LTE-Advanced only)	E-TM 1.1 E-TM 1.2	ACP
6.6.3	Operating band unwanted emissions (SEM)	E-TM 1.1 E-TM 1.2	Spectrum emission mask
6.6.3	Cumulative mask for SEM (LTE-Advanced only)	E-TM 1.1 E-TM 1.2	Spectrum emission mask
6.6.4	Transmitter spurious emission	E-TM 1.1	Spurious emissions
6.7	Transmitter intermodulation	E-TM 1.1	ACP, SEM, spurious emissions

1. All of the measurements are available for single carrier (LTE) or multiple-carrier LTE-Advanced with up to 5 component carriers. Option 1FP is LTE, Option 2FP is LTE-Advanced.
2. These are pre-demodulation channel power measurements. Channel power reading is also available after demodulation under "Error Summary" trace.
3. These measurements are available under "Error Summary" trace in Mod Analysis as well as under "Conformance EVM" measurement.
4. For LTE-Advanced, this measurement is supported for contiguous carrier aggregation and requires analysis bandwidth on X-Series signal analyzer wide enough to cover the aggregated bandwidth.
5. "MIMO Summary"/"MIMO Info Table" traces are used to measure TAE for MIMO and Tx diversity signals. For carrier aggregation, "Cross-carrier Summary" trace is used to measure TAE.

Measurement Summary (continued)

One-button standards-based measurements

Required user equipment (UE) RF transmitter measurements

3GPP TS 36.521-1 paragraph #			Transmitter test	N9080B & W9080B (FDD) N9082B & W9082B (TDD) measurement applications
LTE Rel 8 and up	LTE- Advanced CA	LTE- Advanced UL-MIMO		
6.2.2	6.2.2A	6.2.2B	UE maximum output power (MOP)	
6.2.3	6.2.3A	6.2.3B	Maximum power reduction (MPR)	
6.2.4	6.2.4A	6.2.4B	Additional maximum power reduction (A-MPR)	Channel power
6.2.5	6.2.5A	6.2.5B	Configured UE transmitted output power	
6.3.2	6.3.2A	6.3.2B	Minimum output power	
6.3.3	6.3.3A	6.3.3B	Transmit off power	Channel power or transmit on/off power
6.3.4	6.3.4A	6.3.4B	On/off time mask	Transmit on/off power
6.3.5	6.3.5A	6.3.5B	Power control	Not available
6.5.1	6.5.1A	6.5.1B	Frequency error	Frequency error ¹ and frequency error per slot ²
6.5.2.1	6.5.2A.1	6.5.2B.1	Error vector magnitude (EVM)	EVM ¹
6.5.2.1A	N/A	N/A	PUSCH-EVM with exclusion period	EVM ¹
6.5.2.2	6.5.2A.2	6.5.2B.2	Carrier leakage	IQ offset ¹ and IQ offset per slot ²
6.5.2.3	6.5.2A.3	6.5.2B.3	In-band emissions for non-allocated RB	In-band emissions ²
6.5.2.4	N/A	6.5.2B.4	EVM equalizer spectrum flatness	Equalizer channel frequency response per slot ³
6.6.1	6.6.1A	6.6.1B	Occupied bandwidth	Occupied BW
6.6.2.1	6.6.2.1A	6.6.2.1B	Spectrum emission mask (SEM)	SEM
6.6.2.2	6.6.2.2A	6.6.2.2B	Additional SEM	SEM
6.6.2.3	6.6.2.3A	6.6.2.3B	Adjacent channel leakage power ratio (ACLR)	ACP
6.6.3.1	6.6.3.1A	6.6.3B.1	Transmitter spurious emission	Spurious emissions
6.6.3.2	6.6.3.2A	6.6.3B.2	Spurious emission band UE co-existence	Spurious emissions
6.6.3.3	6.6.3.3A	6.6.3B.3	Additional spurious emissions	Spurious emissions
6.7	6.7A	6.7B	Transmit intermodulation	ACP
N/A	N/A	6.8B	Time alignment	Time offset ¹

1. These values are found in "Error Summary" table under Mod Analysis measurement or under Conformance EVM measurements.

2. These measurements are part of the Mod Analysis measurement. Once in Mod Analysis, they are found under [Trace/Detector] -> {Data} > {Demod Error}.

3. This measurement is part of the Mod Analysis measurement. Once in Mod Analysis, it is found under [Trace/Detector] -> {Data} > {Response}.

Measurement Summary (continued)

Measurement details

All of the RF transmitter measurements as defined by the 3GPP standard, as well as a wide range of additional measurements and analysis tools are available with a press of a button. These measurements are fully remote controllable via the IEC/IEEE bus or LAN, using SCPI commands.

Analog baseband measurements for LTE/LTE-Advanced are available on a PXA or MXA signal analyzer equipped with BBIQ hardware. Supported baseband measurements include all of the modulation quality plus I/Q waveform measurement.

It is important to note that the measurements shown in the LTE FDD and TDD tables are available for a single carrier, while the measurements for LTE-Advanced FDD and TDD columns are available for multiple carriers with up to 5 component carriers.

eNB measurements

Technology	LTE FDD	LTE-Advanced FDD	LTE TDD	LTE-Advanced TDD
Model-Option	N9080B/ W9080B-1FP	N9080B/ W9080B-2FP	N9082B/ W9082B-1FP	N9082B/ W9082B-2FP
Modulation quality (error summary table)				
– EVM (RMS, peak, data, RS)	▪	▪	▪	▪
– Channel power	▪	▪	▪	▪
– RS Tx. power (RSTP)	▪	▪	▪	▪
– OFDM symbol Tx. power (OSTP)	▪	▪	▪	▪
– RS Rx. power (RSRP)	▪	▪	▪	▪
– RSSI	▪	▪	▪	▪
– RS Rx. quality (RSRQ)	▪	▪	▪	▪
– Frequency error	▪	▪	▪	▪
– Common tracking error	▪	▪	▪	▪
– Symbol clock error	▪	▪	▪	▪
– Time offset	▪	▪	▪	▪
– IQ (Offset, gain imbalance, quad error, timing skew)	▪	▪	▪	▪
Conformance EVM	▪	▪	▪	▪
Demodulated error traces				
– EVM vs. frequency (sub-carrier)	▪	▪	▪	▪
– EVM vs. time (symbol)	▪	▪	▪	▪
– EVM vs. resource block	▪	▪	▪	▪
– EVM vs. slot	▪	▪	▪	▪
– Frequency error per slot	▪	▪	▪	▪
– Power vs. resource block	▪	▪	▪	▪
– Power vs. slot	▪	▪	▪	▪
Symbols table				
– Numerical values of demodulated symbols (encoded)	▪	▪	▪	▪
Decoded symbol table				
– Numerical values of demodulated data include demapped, deinterleaved, descrambled, deratematched, and decoded data	▪	▪	▪	▪
Downlink decode table				
– Decode information from PBCH, PDCCH, PHICH, and PCFICH	▪	▪	▪	▪
Frame summary table				
– EVM, power, modulation format, and number of allocated RB and RNTI for all active channels and signals	▪	▪	▪	▪
Cross-carrier summary				
– Time alignment error (TAE) and channel power summary of each CC relative to the selected reference CC		▪		▪

Measurement Summary (continued)

eNB measurements (continued)

Technology	LTE FDD	LTE-Advanced FDD	LTE TDD	LTE-Advanced TDD
Model-Option	N9080B/ W9080B-1FP	N9080B/ W9080B-2FP	N9082B/ W9082B-1FP	N9082B/ W9082B-2FP
TX diversity MIMO (up to 4 Tx antenna) traces				
– Info table				
– RS power	▪	▪	▪	▪
– RS EVM	▪	▪	▪	▪
– RS CTE	▪	▪	▪	▪
– RS timing	▪	▪	▪	▪
– RS phase	▪	▪	▪	▪
– RS symbol clock	▪	▪	▪	▪
– RS frequency	▪	▪	▪	▪
– IQ gain imbalance	▪	▪	▪	▪
– IQ quadrature error	▪	▪	▪	▪
– IQ time skew	▪	▪	▪	▪
– Channel frequency response	▪	▪	▪	▪
– Channel frequency response difference	▪	▪	▪	▪
– Equalizer impulse response	▪	▪	▪	▪
– Common tracking error	▪	▪	▪	▪
Detected allocations trace (resource block vs. symbol)	▪	▪	▪	▪
Response				
– Equalizer channel frequency response	▪	▪	▪	▪
– Instantaneous equalizer channel frequency response	▪	▪	▪	▪
– Equalizer channel frequency response difference	▪	▪	▪	▪
– Instantaneous equalizer channel frequency response difference	▪	▪	▪	▪
– Equalizer impulse response	▪	▪	▪	▪
Channel power	▪	▪	▪	▪
ACP	▪	▪	▪	▪
Cumulative ACLR (CACLR)		▪		▪
Transmit on/off power			▪	▪
Spectrum emission mask (SEM)	▪	▪	▪	▪
Cumulative SEM		▪		▪
Spurious emissions	▪	▪	▪	▪
Occupied bandwidth	▪	▪	▪	▪
CCDF	▪	▪	▪	▪
Monitor spectrum	▪	▪	▪	▪
I/Q waveform	▪	▪	▪	▪

Measurement Summary (continued)

UE measurements

Technology	LTE FDD	LTE-Advanced FDD	LTE TDD	LTE-Advanced TDD
Model-Option	N9080B/ W9080B-1FP	N9080B/ W9080B-2FP	N9082B/ W9082B-1FP	N9082B/ W9082B-2FP
Modulation quality (error summary trace)				
– EVM (RMS, peak, data, RS)	▪	▪	▪	▪
– Frequency error	▪	▪	▪	▪
– Common tracking error	▪	▪	▪	▪
– Symbol clock error	▪	▪	▪	▪
– Time offset	▪	▪	▪	▪
– IQ (offset, gain imbalance, quad error, timing skew)	▪	▪	▪	▪
– Channel power	▪	▪	▪	▪
– In-band emissions result without carrier aggregation	▪	▪	▪	▪
– In-band emissions result with carrier aggregation	▪		▪	
– Spectral flatness result	▪	▪	▪	▪
Conformance EVM	▪	▪	▪	▪
In-band emissions without carrier aggregation	▪	▪	▪	▪
In-band emissions with carrier aggregation		▪		▪
Spectrum flatness (eq. ch freq response per slot)	▪	▪	▪	▪
Demodulated error traces				
– EVM vs. frequency (sub-carrier)	▪	▪	▪	▪
– EVM vs. time (symbol)	▪	▪	▪	▪
– EVM vs. resource block	▪	▪	▪	▪
– EVM vs. slot	▪	▪	▪	▪
– IQ offset per slot	▪	▪	▪	▪
– Frequency error per slot	▪	▪	▪	▪
– Power vs. resource block	▪	▪	▪	▪
– Power vs. slot	▪	▪	▪	▪
Symbols table				
– Numerical values of demodulated symbols (encoded)	▪	▪	▪	▪
Decoded symbol table				
– Numerical values of demodulated data and descrambled data for PUSCH	▪	▪	▪	▪
Frame summary table				
– EVM, power, modulation format and number of allocated RB for all active channels and signals	▪	▪	▪	▪
Detected allocations trace (resource block vs. symbol)	▪	▪	▪	▪
Response				
– Equalizer channel frequency response	▪	▪	▪	▪
– Instantaneous equalizer channel frequency response	▪	▪	▪	▪
– Equalizer channel frequency response difference	▪	▪	▪	▪
– Instantaneous equalizer channel frequency response difference	▪	▪	▪	▪
– Equalizer impulse response	▪	▪	▪	▪
– Equalizer channel frequency response per slot	▪	▪	▪	▪
Channel power	▪	▪	▪	▪
ACP	▪	▪	▪	▪
Transmit on/off power	▪	▪	▪	▪
Spectrum emission mask (SEM)	▪	▪	▪	▪
Spurious emissions	▪	▪	▪	▪
Occupied bandwidth	▪	▪	▪	▪
CCDF	▪	▪	▪	▪
Monitor spectrum	▪	▪	▪	▪
I/Q waveform	▪	▪	▪	▪

Key Specifications

Definitions

- Specifications describe the performance of parameters.
- The specifications apply to single carrier case only, unless otherwise stated.
- 95th percentile values indicate the breadth of the population ($\approx 2\sigma$) of performance tolerances expected to be met in 95% of cases with a 95% confidence.
- Typical values are designated with the abbreviation "typ." These are performance beyond specification that 80% of the units exhibit with a 95% confidence.
- Nominal values are designated with the abbreviation "nom." These values indicate expected performance, or describe product performance that is useful in the application of the product.

Note: Data subject to change.

Supported standards

Technology	LTE FDD/TDD	LTE-Advanced FDD/TDD
Model-Option	N9080B/W9080B-1FP N9082B/W9082B-1FP	N9080B/W9080B-2FP N9082B/W9082B-2FP
Standard versions	36.211 V9.1.0 (March 2010) 36.212 V9.4.0 (September 2011) 36.213 V9.3.0 (September 2010) 36.214 V9.2.0 (June 2010) 36.141 V9.10.0 (July 2012) 36.521-1 V9.8.0 (March 2012)	36.211 V10.7.0 (March 2013) 36.212 V10.7.0 (December 2012) 36.213 V10.9.0 (March 2013) 36.214 V10.12.0 (March 2013) 36.141 V11.4.0 (March 2013) 36.521-1 V10.5.0 (March 2013)
Signal structure	FDD Frame Structure Type 1 TDD Frame Structure Type 2 Special subframe configurations 0-8	FDD Frame Structure Type 1 TDD Frame Structure Type 2 Special subframe configurations 0-9
Signal direction	Uplink and downlink UL/DL configurations 0-6	Uplink and downlink UL/DL configurations 0-6
Signal bandwidth	1.4 MHz (6 RB), 3 MHz (15 RB), 5 MHz (25 RB), 10 MHz (50 RB), 15 MHz (75 RB), 20 MHz (100 RB)	Bandwidth per component carrier: 1.4 MHz (6 RB), 3 MHz (15 RB), 5 MHz (25 RB), 10 MHz (50 RB), 15 MHz (75 RB), 20 MHz (100 RB)
Number of component carriers	1	1, 2, 3, 4, or 5
Physical signals		
– Downlink	PBCH, PCFICH, PHICH, PDCCH, PDSCH, PMCH	
– Uplink	PUCCH, PUSCH, PRACH	
Physical channels		
– Downlink	P-SS, S-SS, C-RS, UE-RS, P-PS (positioning), MBSFN-RS	P-SS, S-SS, C-RS, UE-RS, P-PS (positioning), MBSFN-RS, CSI-RS
– Uplink	PUCCH-DMRS, PUSCH-DMRS, S-RS (sounding)	PUCCH-DMRS, PUSCH-DMRS, S-RS (sounding)

For a complete list of specifications refer to the appropriate specifications guide.

PXA: http://www.keysight.com/find/pxa_specifications

MXA: http://www.keysight.com/find/mxa_specifications

EXA: http://www.keysight.com/find/exa_specifications

CXA: http://www.keysight.com/find/cxa_specifications

Key Specifications (continued)

Description		PXA	MXA	EXA	CXA		
Channel power							
Minimum power at RF input		-50 dBm (nom)					
Power accuracy		± 0.63 dB	± 0.82 dB	± 1.04 dB	± 1.33 dB		
Power accuracy (95% confidence)		± 0.19 dB	± 0.23 dB	± 0.27 dB	± 0.61 dB		
Measurement floor (@ 10 MHz BW)		-81.7 dBm (nom)	-79.7 dBm (nom)	-76.7 dBm (nom)	-72.7 dBm (nom)		
Transmit on/off power (only applies to N9082B/W9082B)							
Burst type		Traffic, UpPTS, DwPTS, SRS, PRACH					
Measurement time		Up to 20 slots					
Dynamic range for 5 MHz BW ¹		124.5 dB (nom)	124.5 dB (nom)	122.5 dB (nom)	119.5 dB (nom)		
Adjacent channel power							
Minimum power at RF input		-36 dBm (nom)					
Accuracy							
Radio	Offset frequency						
MS	Adjacent	± 0.07 dB (5 MHz)	± 0.13 dB (5 MHz)	± 0.16 dB (5 MHz)	± 0.37 dB (5 MHz)		
		± 0.11 dB (10 MHz)	± 0.20 dB (10 MHz)	± 0.24 dB (10 MHz)	± 0.63 dB (10 MHz)		
		± 0.21 dB (20 MHz)	± 0.38 dB (20 MHz)	± 0.41 dB (20 MHz)	± 0.92 dB (20 MHz)		
(ACPR range -33 to -27 dBc with Opt ML)							
BTS	Adjacent	± 0.23 dB (5 MHz)	± 0.57 dB (5 MHz)	± 1.03 dB (5 MHz)	± 2.16 dB (5 MHz)		
		± 0.33 dB (10 MHz)	± 0.82 dB (10 MHz)	± 1.29 dB (10 MHz)	± 3.03 dB (10 MHz)		
		± 0.52 dB (20 MHz)	± 1.19 dB (20 MHz)	± 2.04 dB (20 MHz)	± 4.49 dB (20 MHz)		
(ACPR range -48 to -42 dBc with Opt ML)							
BTS	Alternate	± 0.11 dB (5 MHz)	± 0.21 dB (5 MHz)	± 0.24 dB (5 MHz)	± 0.91 dB (5 MHz)		
		± 0.21 dB (10 MHz)	± 0.35 dB (10 MHz)	± 0.39 dB (10 MHz)	± 1.55 dB (10 MHz)		
		± 0.40 dB (20 MHz)	± 0.65 dB (20 MHz)	± 0.74 dB (20 MHz)	± 2.48 dB (20 MHz)		
(ACPR range -48 to -42 dBc with Opt ML)							
Dynamic range E-UTRA							
Offset	Channel BW						
Adjacent	5 MHz	83.5 dB (nom) (Opt ML -8.5 dBm)	74.2 dB (nom) (Opt ML -18.4 dBm)	70.0 dB (nom) (Opt ML -16.5 dBm)	66.8 dB (nom) (Opt ML -20.3 dBm)		
		Adjacent	10 MHz	82.1 dB (nom) (Opt ML -8.3 dBm)	73.8 dB (nom) (Opt ML -18.4 dBm)	69.3 dB (nom) (Opt ML -16.5 dBm)	67.6 dB (nom) (Opt ML -20.3 dBm)
				Adjacent	20 MHz	Not available	71.7 dB (nom) (Opt ML -18.2 dBm)
Alternate	5 MHz	86.7 dB (nom) (Opt ML -8.5 dBm)	77.6 dB (nom) (Opt ML -18.6 dBm)			75.8 dB (nom) (Opt ML -16.6 dBm)	71.1 dB (nom) (Opt ML -20.3 dBm)
		Alternate	10 MHz	83.7 dB (nom) (Opt ML -8.3 dBm)	75.1 dB (nom) (Opt ML -18.4 dBm)	73.2 dB (nom) (Opt ML -16.3 dBm)	68.0 dB (nom) (Opt ML -20.3 dBm)
Alternate	20 MHz			Not available	72.1 dB (nom) (Opt ML -18.2 dBm)	70.3 dB (nom) (Opt ML -16.3 dBm)	65.0 dB (nom) (Opt ML -20.3 dBm)
		Dynamic range UTRA					
Offset	Channel BW						
2.5 MHz	5 MHz	86.2 dB (nom) (Opt ML -8.5 dBm)	75.9 dB (nom) (Opt ML -18.5 dBm)	70.5 dB (nom) (Opt ML -16.6 dBm)	65.8 dB (nom) (Opt ML -20.3 dBm)		
		2.5 MHz	10 MHz	84.2 dB (nom) (Opt ML -8.3 dBm)	76.2 dB (nom) (Opt ML -18.4 dBm)	70.5 dB (nom) (Opt ML -16.4 dBm)	70.6 dB (nom) (Opt ML -20.3 dBm)
				2.5 MHz	20 MHz	Not available	75.0 dB (nom) (Opt ML -18.2 dBm)
7.5 MHz	5 MHz	87.3 dB (nom) (Opt ML -8.7 dBm)	78.4 dB (nom) (Opt ML -18.5 dBm)			76.5 dB (nom) (Opt ML -16.6 dBm)	71.1 dB (nom) (Opt ML -20.3 dBm)
		7.5 MHz	10 MHz	87.0 dB (nom) (Opt ML -8.4 dBm)	78.6 dB (nom) (Opt ML -18.4 dBm)	76.5 dB (nom) (Opt ML -16.4 dBm)	71.9 dB (nom) (Opt ML -20.3 dBm)
7.5 MHz	20 MHz			Not available	78.1 dB (nom) (Opt ML -18.2 dBm)	75.7 dB (nom) (Opt ML -16.3 dBm)	71.8 dB (nom) (Opt ML -20.3 dBm)

1. This dynamic range is for the case of 5 MHz information bandwidth. For other information bandwidths, the dynamic range can be derived using the following equation: Dynamic Range = Dynamic Range for 5 MHz - 10*log₁₀(Info BW/5.0e6).

Key Specifications (continued)

Description	PXA	MXA	EXA	CXA
Spectrum emission mask				
Dynamic range				
– 5 MHz	82.9 (86.8 dB typ)	76.2 (82.9 dB typ)	72.6 (79.4 dB typ)	69.0 (75.4 dB typ)
– 10 MHz	86.6 (90.7 dB typ)	77.8 (83.8 dB typ)	73.5 (80.3 dB typ)	69.3 (75.5 dB typ)
– 20 MHz	84.3 (89.7 dB typ)	78.2 (84.9 dB typ)	73.4 (80.6 dB typ)	69.8 (76.0 dB typ)
Sensitivity	–98.5 (–101.5 dBm typ)	–94.5 (–99.5 dBm typ)	–92.5 (–96.5 dBm typ)	–86.5 (–92.5 dBm typ)
Accuracy				
– Relative	± 0.06 dB	± 0.13 dB	± 0.13 dB	± 0.33 dB
– Absolute	± 0.62 (± 0.20 dB 95%)	± 0.88 (± 0.27 dB 95%)	± 1.15 (± 0.31 dB 95%)	± 1.53 (± 0.97 dB 95%)
Spurious emissions				
Dynamic range, relative	88.8 (92.1 dB typ)	81.3 (82.2 dB typ)	76.9 (77.4 dB typ)	70.7 (75.9 dB typ)
Sensitivity, absolute	–88.5 (–91.5 dBm typ)	–84.5 (–89.5 dBm typ)	–82.5 (–86.5 dBm typ)	–76.5 (–82.5 dBm typ)
Accuracy (attenuation = 10 dB)	± 0.19 dB (95%)	± 0.29 dB (95%)	± 0.38 dB (95%)	± 0.81 dB (95%)
– Frequency range	20 Hz to 3.6 GHz	20 Hz to 3.6 GHz	9 kHz to 3.6 GHz	100 kHz to 3.0 GHz
– Frequency range	± 1.08 dB (95%)	± 1.17 dB (95%)	± 1.22 dB (95%)	± 1.80 dB (95%)
	3.5 GHz to 8.4 GHz	3.5 GHz to 8.4 GHz	3.5 GHz to 7.0 GHz	3.0 GHz to 7.5 GHz
– Frequency range	± 1.48 dB (95%)	± 1.54 dB (95%)	± 1.59 dB (95%)	
	8.3 GHz to 13.6 GHz	8.3 GHz to 13.6 GHz	6.9 GHz to 13.6 GHz	
Occupied bandwidth				
Minimum power at RF input	–30 dBm (nom)			
Frequency accuracy	± 10 kHz (RBW = 30 kHz, Number of points = 1001, Span = 10 MHz)			
Modulation analysis				
Input range	Signal level within one range step of overload			
OSTP/RSTP¹				
Absolute accuracy	± 0.21 dB (nom)	± 0.27 dB (nom)	± 0.30 dB (nom)	± 0.61 dB
EVM floor for downlink (OFDMA)²				
Signal bandwidth				
– 5 MHz	0.34% (–49.3 dB) 0.28% (–51.2 dB) nom	0.36% (–48.8 dB)	0.68% (–43.3 dB)	0.63% (–44.0 dB) nom
– 10 MHz	0.35% (–49.1 dB) 0.31% (–50.3 dB) nom	0.36% (–48.8 dB)	0.68% (–43.6 dB)	0.64% (–43.8 dB) nom
– 20 MHz	0.39% (–48.1 dB) 0.34% (–49.5 dB) nom	0.40% (–47.9 dB)	0.72% (–43.0 dB)	0.70% (–43.0 dB) nom
EVM floor for downlink (OFDMA) with Option BBA				
Signal bandwidth				
– 5 MHz	0.18% (–54.8 dB) nom	0.18% (–54.8 dB) nom		
– 10 MHz	0.18% (–54.8 dB) nom	0.18% (–54.8 dB) nom		
– 20 MHz	0.18% (–54.8 dB) nom	0.18% (–54.8 dB) nom		
EVM accuracy for Downlink (OFDMA)³				
EVM range: 0 to 8%	± 0.3% nom	± 0.3% nom	± 0.3% nom	± 0.3% nom
EVM floor for uplink (SC-FDMA)²				
Signal bandwidth				
– 5 MHz	0.31% (–50.1 dB) 0.21% (–53.5 dB) nom	0.35% (–49.1 dB)	0.66% (–43.6 dB)	0.60% (–44.4 dB) nom
– 10 MHz	0.32% (–49.8 dB) 0.21% (–53.5 dB) nom	0.35% (–49.1 dB)	0.66% (–43.6 dB)	0.61% (–44.2 dB) nom
– 20 MHz	0.35% (–49.1 dB) 0.22% (–53.2 dB) nom	0.40% (–47.9 dB)	0.70% (–43.0 dB)	0.63% (–44.0 dB) nom

1. The accuracy specification applies when EVM is less than 1% and no power boost is applied on reference signal.

2. For MXA and EXA instruments with serial number prefix ≥ MY/SG/US5233 and ≥ MY/SG/US5340, which ship standard with N9020A-EP2 and N9010A-EP3. Refer to the LTE section in the MXA and EXA specification guides for more information: www.keysight.com/find/mxa_specifications; www.keysight.com/find/exa_specifications.

3. The accuracy specification applies when the EVM to be measured is well above the measurement floor. When the EVM does not greatly exceed the floor, the errors due to the floor add to the accuracy errors. Refer to specification guide for information on calculating the errors due to the floor.

Key Specifications (continued)

Description	PXA	MXA	EXA	CXA
Frequency error				
Lock range	$\pm 2.5 \times$ subcarrier spacing = 37.5 kHz for default 15 kHz subcarrier spacing (nom)			
Accuracy	$\pm 1 \text{ Hz} + tfa^1$ (nom)			
Time offset ²				
Absolute frame offset accuracy	$\pm 20 \text{ ns}$	$\pm 20 \text{ ns}$	$\pm 20 \text{ ns}$	$\pm 20 \text{ ns}$
Relative frame offset accuracy	$\pm 5 \text{ ns (nom)}$	$\pm 5 \text{ ns (nom)}$	$\pm 5 \text{ ns (nom)}$	$\pm 5 \text{ ns (nom)}$
MIMO RS timing accuracy	$\pm 5 \text{ ns (nom)}$	$\pm 5 \text{ ns (nom)}$	$\pm 5 \text{ ns (nom)}$	$\pm 5 \text{ ns (nom)}$

1. tfa = transmitter frequency x frequency reference accuracy.

2. The accuracy specification applies when EVM is less than 1% and no power boost is applied for resource elements.

Software Licensing and Configuration

Choose from two license types:

- Fixed, perpetual license:
This allows you to run the application in the X-Series analyzer in which it is initially installed.
- Transportable, perpetual license:
This allows you to run the application in the X-Series analyzer in which it is initially installed, plus it may be transferred from one X-Series analyzer to another.

You Can Upgrade!

Options can be added after your initial purchase.

All of our X-Series application options are license-key upgradeable.



For more information, please visit the respective product Web pages.

LTE/LTE-Advanced FDD measurement application

Model-Option	Description	Additional information
N9080B/W9080B-1FP	LTE FDD measurement application, fixed perpetual license	
N9080B/W9080B-1TP	LTE FDD measurement application, transportable perpetual license	
N9080B/W9080B-2FP	LTE-Advanced FDD measurement application, fixed perpetual license	Requires 1FP
N9080B/W9080B-2TP	LTE-Advanced FDD measurement application, transportable perpetual license	Requires 1TP

Note: N9080B/W9080B application requires Windows 7 operating system in X-Series signal analyzers. For more information, see hardware configurations.

LTE/LTE-Advanced TDD measurement application

Model-Option	Description	Additional information
N9082B/W9082B-1FP	LTE TDD measurement application, fixed perpetual license	
N9082B/W9082B-1TP	LTE TDD measurement application, transportable perpetual license	
N9082B/W9082B-2FP	LTE-Advanced TDD measurement application, fixed perpetual license	Requires 1FP
N9082B/W9082B-2TP	LTE-Advanced TDD measurement application, transportable perpetual license	Requires 1TP

Note: N9082B/W9082B application requires Windows 7 operating system in X-Series signal analyzers. For more information, see hardware configurations.

Signal Studio Software Updates

To update previously purchased N/W9080B or N/W9082B software to include the latest feature updates, you can purchase minor enhancement update fixed perpetual licenses as follows:

www.keysight.com/find/N9080B-MEU
www.keysight.com/find/W9080B-MEU
www.keysight.com/find/N9082B-MEU
www.keysight.com/find/W9082B-MEU

Hardware configuration

N9030A PXA signal analyzer

Description	Model-Option	Additional information
3.6, 8.4, 13.6, 26.5, 43, 44, or 50 GHz frequency range	N9030A-503, -508, -513, -526, -543, -544, or -550	One required
Operating system, Windows Embedded Standard 7	N9030A-W7X	Required; ships standard on new instruments
Analog baseband IQ (BBIQ) inputs	N9030A-BBA	Required for analog baseband measurement
25, 40, 85, or 160 MHz analysis bandwidth	N9030A-B25, -B40, -B85, -B1X	See footnote 1
Precision frequency reference	N9030A-PFR	Recommended
Electronic attenuator, 3.6 GHz	N9030A-EA3	Recommended
Preamplifier, 3.6, 8.4, 13.6, 26.5, 43, 44, or 50 GHz	N9030A-P03, -P08, -P13, -P26, -P43, -P44, or -P50	One recommended

N9020A MXA signal analyzer

Description	Model-Option	Additional information
3.6, 8.4, 13.6, or 26.5 GHz frequency range	N9020A-503, -508, -513, or -526	One required
Operating system, Windows Embedded Standard 7	N9020A-W7X	Required; ships standard on new instruments
Analog baseband IQ (BBIQ) inputs	N9020A-BBA	Required for analog baseband measurement
25, 40, 85, 125, or 160 MHz analysis bandwidth	N9020A-B25, -B40, -B85, -B1A, -B1X	See footnote 1
Precision frequency reference	N9020A-PFR	Recommended
Electronic attenuator, 3.6 GHz	N9020A-EA3	Recommended
Preamplifier, 3.6, 8.4, 13.6, or 26.5 GHz	N9020A-P03, -P08, -P13, or -P26	One recommended

N9010A EXA signal analyzer

Description	Model-Option	Additional information
3.6, 7.0, 13.6, 26.5, 32, or 44 GHz frequency range	N9010A-503, -507, -513, -526, -532, or -544	One required
Operating system, Windows Embedded Standard 7	N9010A-W7X	Required; ships standard on new instruments
25, 40 MHz analysis bandwidth	N9010A-B25, B40	See footnote 1
Precision frequency reference	N9010A-PFR	Recommended
Electronic attenuator, 3.6 GHz	N9010A-EA3	Recommended
Preamplifier, 3.6, 7.0, 13.6, 26.5, 32, or 44 GHz	N9010A-P03, -P07, -P13, -P26 -P32, or -P44	One recommended

N9000A CXA signal analyzer

Description	Model-Option	Additional information
3, 7.5, 13.6 or 26.5 GHz frequency range	N9000A-503, -507, -513, -526	One required
Operating system, Windows Embedded Standard 7	N9000A-W7S	Required; ships standard
25 MHz analysis bandwidth	N9000A-B25	10 MHz standard; see footnote 1
Precision frequency reference	N9000A-PFR	Recommended
Fine resolution step attenuator	N9000A-FSA	Recommended
Preamplifier, 3, 7.5, 13.6, or 26.5 GHz	N9000A-P03, -P07, -P13, -P26	One recommended

1. One required; LTE-Advanced demodulation offers the ability to use a simultaneous acquisition mode to capture multiple component carriers simultaneously requiring an analysis BW larger than the sum of the combined carriers, or a sequential capture mode which allows you to use a 25 MHz bandwidth to capture each carrier sequentially and then display them all at once. LTE-Advanced TDD transmit on/off power measurement is the only measurement that requires bandwidth wide enough to cover the full aggregated bandwidth

Additional Information

Literature

3GPP Long Term Evolution: System Overview, Product Development, and Test Challenges, Application Note, literature number 5989-8139EN

Introducing LTE-Advanced, Application Note, literature number 5990-6706EN

Stimulus-Response Testing for LTE Components, Application Note, literature number 5990-5149EN

Measuring ACLR Performance in LTE Transmitters, Application Note, literature number 5990-5089EN

TD-LTE E-UTRA Base Station Transmit ON/OFF Power Measurement Using a Keysight X-Series Signal Analyzer, Application Note, literature number 5990-5989EN

Web

Measurement, User's and Programmer guides can be found on the product Web pages of the respective document libraries.

N9080B: www.keysight.com/find/N9080B

W9080B: www.keysight.com/find/W9080B

N9082B: www.keysight.com/find/N9082B

W9082B: www.keysight.com/find/W9082B

Application pages:

www.keysight.com/find/lte

www.keysight.com/find/lteadvanced

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